# International Rectifier

- Logic Level Gate Drive
- Ultra Low On-Resistance
- Surface Mount (IRLR3410)
- Straight Lead (IRLU3410)
- Advanced Process Technology
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

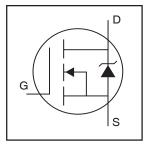
#### **Description**

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve the lowest possible on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient device for use in a wide variety of applications.

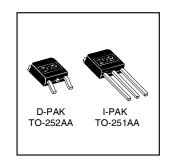
The D-PAK is designed for surface mounting using vapor phase, infrared, or wave soldering techniques. The straight lead version (IRFU series) is for throughhole mounting applications. Power dissipation levels up to 1.5 watts are possible in typical surface mount applications.

# IRLR/U3410PbF

HEXFET® Power MOSFET



$$V_{DSS} = 100V$$
 $R_{DS(on)} = 0.105\Omega$ 
 $I_{D} = 17A$ 



#### **Absolute Maximum Ratings**

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	17	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	12	A
I <sub>DM</sub>	Pulsed Drain Current ①⑤	60	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	79	W
	Linear Derating Factor	0.53	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	± 16	V
E <sub>AS</sub>	Single Pulse Avalanche Energy@®	150	mJ
I <sub>AR</sub>	Avalanche Current①⑤	9.0	A
E <sub>AR</sub>	Repetitive Avalanche Energy ① ⑤	7.9	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns
TJ	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.9	
$R_{\theta JA}$	Junction-to-Ambient (PCB mount) **		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient		110	

#### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	100	. ур.		V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.122		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
= * (BH)B33 = *3	Static Drain-to-Source On-Resistance			0.105	., .	V <sub>GS</sub> = 10V, I <sub>D</sub> = 10A ④
R <sub>DS(on)</sub>				0.125	W	V <sub>GS</sub> = 5.0V, I <sub>D</sub> = 10A ⊕
DO(OH)				0.155		V <sub>GS</sub> = 4.0V, I <sub>D</sub> = 9.0A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.0		2.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
<b>9</b> fs	Forward Transconductance	7.7			S	V <sub>DS</sub> = 25V, I <sub>D</sub> = 9.0A <sup>⑤</sup>
	Drain-to-Source Leakage Current			25		V <sub>DS</sub> = 100V, V <sub>GS</sub> = 0V
I <sub>DSS</sub>				250	μA	V <sub>DS</sub> = 80V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 150°C
	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 16V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	IIA	V <sub>GS</sub> = -16V
Qg	Total Gate Charge			34		I <sub>D</sub> = 9.0A
Q <sub>gs</sub>	Gate-to-Source Charge			4.8	nC	$V_{DS} = 80V$
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge			20		V <sub>GS</sub> = 5.0V, See Fig. 6 and 13 ⊕ ⑤
t <sub>d(on)</sub>	Turn-On Delay Time		7.2			$V_{DD} = 50V$
t <sub>r</sub>	Rise Time		53		200	$I_{D} = 9.0A$
t <sub>d(off)</sub>	Turn-Off Delay Time		30		ns	$R_G = 6.0\Omega, V_{GS} = 5.0V$
t <sub>f</sub>	Fall Time		26			$R_D = 5.5\Omega$ , See Fig. 10 $\oplus$ $\odot$
L <sub>D</sub>	Internal Drain Inductance		4.5		nH	Between lead,
						6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance		7.5			from package
						and center of die contact® s
C <sub>iss</sub>	Input Capacitance		800			V <sub>GS</sub> = 0V
Coss	Output Capacitance		160		pF	$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		90		1	f = 1.0MHz, See Fig. 5®

#### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions	
Is	Continuous Source Current	1		17 A		MOSFET symbol	
	(Body Diode)				showing the		
I <sub>SM</sub>	Pulsed Source Current		_	60	] ^`	integral reverse	
	(Body Diode) ①⑤					p-n junction diode.	
V <sub>SD</sub>	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$ , $I_S = 9.0A$ , $V_{GS} = 0V$ ④	
t <sub>rr</sub>	Reverse Recovery Time		140	210	ns	$T_J = 25^{\circ}C, I_F = 9.0A$	
Q <sub>rr</sub>	Reverse RecoveryCharge		740	1100	nC	di/dt = 100A/µs ⊕⑤	
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )					

#### Notes:

- $\ensuremath{\mathbb{O}}$  Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- ②  $V_{DD} = 25V$ , starting  $T_J = 25$ °C, L = 3.1mH  $R_G = 25\Omega$ ,  $I_{AS} = 9.0A$ . (See Figure 12)
- 4 Pulse width  $\leq 300 \mu s$ ; duty cycle  $\leq 2\%$
- ⑤ Uses IRL530N data and test conditions
- T<sub>J</sub> ≤ 175°C
- $\begin{tabular}{l} \begin{tabular}{l} \begin{tab$ center of die contact
- $^{\star\star}$  When mounted on 1" square PCB (FR-4 or G-10 Material ) . For recommended footprint and soldering techniques refer to application note #AN-994

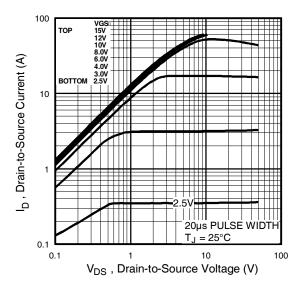


Fig 1. Typical Output Characteristics

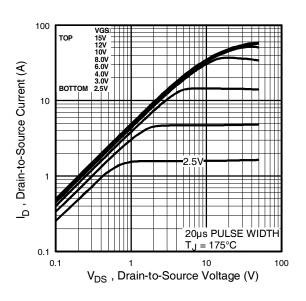


Fig 2. Typical Output Characteristics

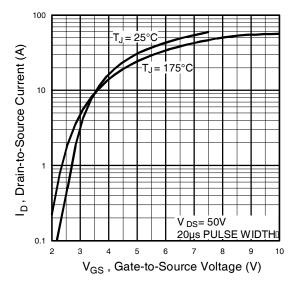
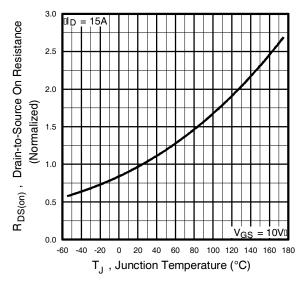
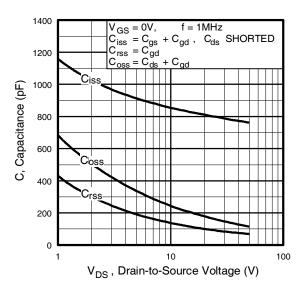


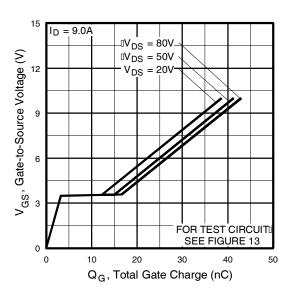
Fig 3. Typical Transfer Characteristics



**Fig 4.** Normalized On-Resistance Vs. Temperature



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

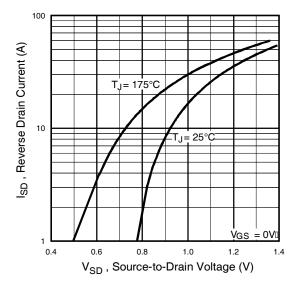


Fig 7. Typical Source-Drain Diode Forward Voltage

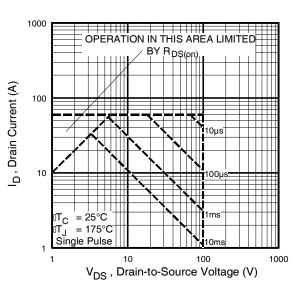
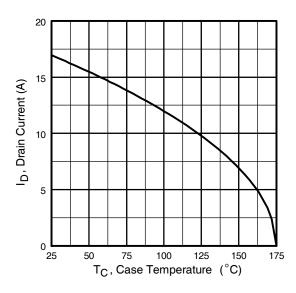


Fig 8. Maximum Safe Operating Area



**Fig 9.** Maximum Drain Current Vs. Case Temperature

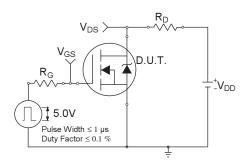


Fig 10a. Switching Time Test Circuit

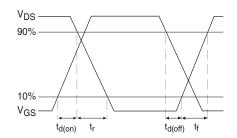


Fig 10b. Switching Time Waveforms

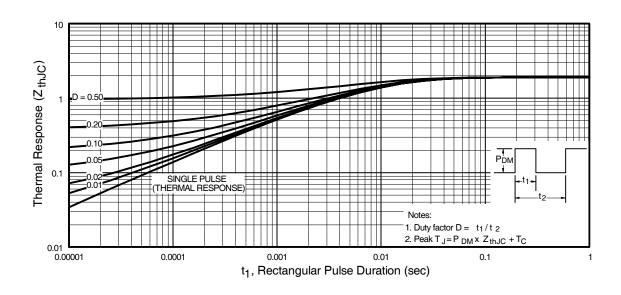


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

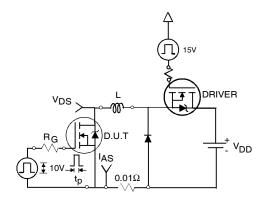


Fig 12a. Unclamped Inductive Test Circuit

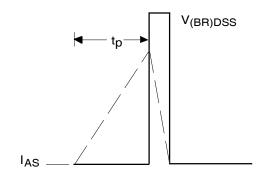


Fig 12b. Unclamped Inductive Waveforms

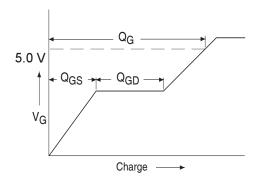


Fig 13a. Basic Gate Charge Waveform

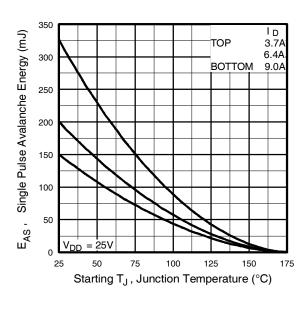


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

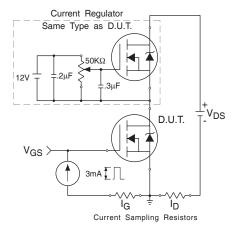
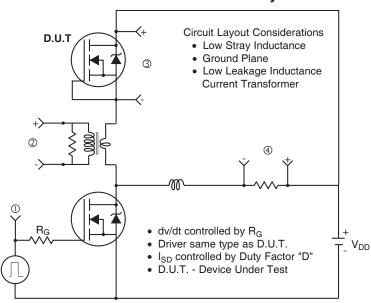
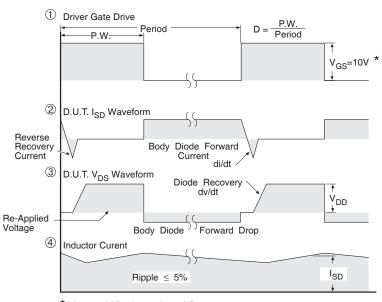


Fig 13b. Gate Charge Test Circuit

#### Peak Diode Recovery dv/dt Test Circuit





\* V<sub>GS</sub> = 5V for Logic Level Devices

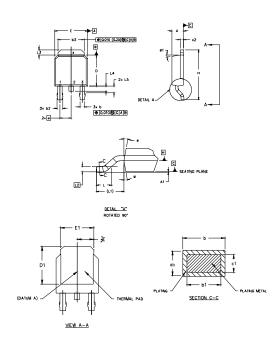
Fig 14. For N-Channel HEXFETS

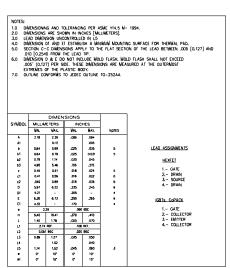
International

TOR Rectifier

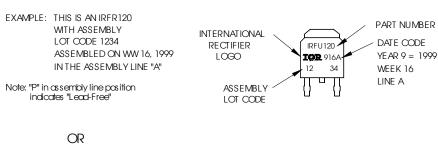
#### D-Pak (TO-252AA) Package Outline

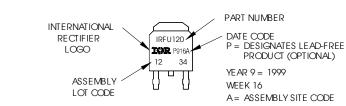
Dimensions are shown in millimeters (inches)





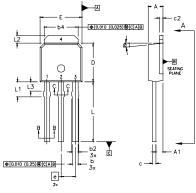
# D-Pak (TO-252AA) Part Marking Information

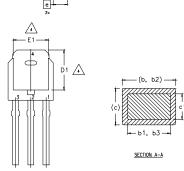




# I-Pak (TO-251AA) Package Outline

Dimensions are shown in millimeters (inches)





- DIMENSIONING AND TOLERANCING PER ASME Y14,5 M- 1994.
- DIMENSIONING AND TOLERANCING PER ASMETT4.5 M = 1994.

  DIMENSIONS ARE SHOWN IN MILLIERTERS (INCHES). LD FLASH SHALL NOT EXCEED O.005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

  THERMAL PAD CONTOUR OPTION WITHIN DIMENSION 64, L2, E1 & D1. LEAD DIMENSION UNCONTROLLED IN L3.

DIMENSION 61, 63 APPLY TO BASE METAL ONLY. OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA. CONTROLLING DIMENSION: INCHES.

DIMENSIONS

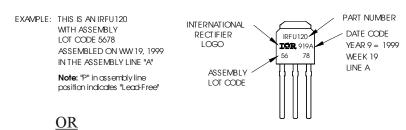
SYMBOL	MILLIN	ETERS	INCHES		
	MIN.	MAX.	MIN.	MAX.	NOTES
A	2.18	2.39	0.086	.094	
A1	0.89	1,14	0.035	0.045	
ь	0.64	0.89	0.025	0.035	
ь1	0.64	0.79	0.025	0.031	4
b2	0.76	1,14	0.030	0.045	
b3	0.76	1,04	0.030	0.041	
b4	5.00	5,46	0,195	0,215	4
с	0.46	0,61	0.018	0.024	
¢1	0.41	0.56	0.016	0.022	
c2	.046	0.86	0,018	0.035	
D	5.97	6.22	0.235	0,245	3, 4
D1	5.21	-	0.205	-	4
E	6.35	6.73	0.250	0.265	3, 4
E1	4.32	-	0,170	-	4
e	2,29		0.090 BSC		
L	8.89	9.60	0.350	0.380	
11	101	2 20	0.075	n non	

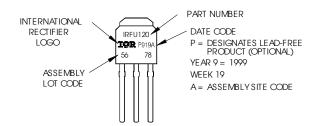
# HEXFET

LEAD ASSIGNMENTS

- 1.- GATE 2.- DRAIN 3.- SOURCE 4.- DRAIN
- 1,27 1,52 15' 0,050 0,060 15° L2 L3 ø1 0.035

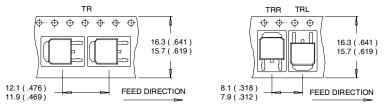
## I-Pak (TO-251AA) Part Marking Information





## D-Pak (TO-252AA) Tape & Reel Information

Dimensions are shown in millimeters (inches)

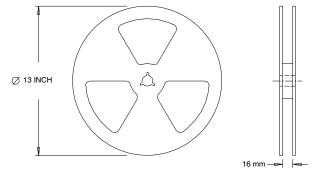


- NOTES:

  1. CONTROLLING DIMENSION: MILLIMETER.

  2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).

  3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:
1. OUTLINE CONFORMS TO EIA-481.

Data and specifications subject to change without notice.



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Note: For the most current drawings please refer to the IR website at: <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>